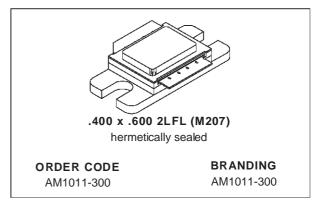
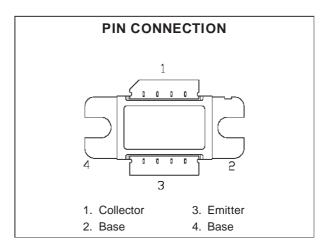


AM1011-300

RF & MICROWAVE TRANSISTORS AVIONICS APPLICATIONS

- REFRACTORY/GOLD METALLIZATION
- EMITTER SITE BALLASTING
- LOW RF THERMAL RESISTANCE
- INPUT/OUTPUT MATCHING
- OVERLAY GEOMETRY
- METAL/CERAMIC HERMETIC PACKAGE
- $P_{OUT} = 325$ W MIN. WITH 7.7 dB GAIN
- 1030/1090 MHZ OPERATION





DESCRIPTION

The AM1011-300 is a rugged, Class C common base device specifically designed for new Mode-S interrogator and transponder applications.

Minimal amplitude droop over the heavy Mode-S pulse burst is guaranteed by a thermal design incorporating an overlay site-ballasted die geometry.

ABSOLUTE MAXIMUM RATING	GS ($T_{case} = 25^{\circ}C$)
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Symbol	Parameter	Value	Unit
PDISS	Power Dissipation $(T_C \le 100^{\circ}C)^*$	1070	W
Ι _C	Device Current*	36	A
Vcc	Collector-Supply Voltage*	43	V
TJ	Junction Temperature (Pulsed RF operation)	+250	°C
T _{STG}	Storage Temperature	- 65 to +200	°C

THERMAL DATA

R _{TH(j-c)}	Junction-Case Thermal Resistance*	0.14	°C/W
*Applies only to rated R	F amplifier operation.		

ELECTRICAL SPECIFICATIONS ($T_{case} = 25^{\circ}C$)

STATIC

Symbol	Test Conditions	Value			Unit		
	Test Conditions		Min.	Тур.	Max.	Unit	
ВVсво	I _C = 75 mA	$I_E = 0 \text{ mA}$		65	_		V
BV _{CES}	I _C = 75 mA	$V_{BE} = 0 V$		65			V
BV _{EBO}	I _C = 25 mA	$I_{C} = 0 \text{ mA}$		3.0	—	—	V
I _{CES}	$V_{CE} = 40 V$	$V_{BE} = 0 V$				30	mA
h _{FE}	$V_{CE} = 5 V$	I _C = 10 A		10		_	

DYNAMIC

Symbol	Test Conditions		Value			11:0:4	
Symbol			Min.	Тур.	Max.	Unit	
Роит	f = 1090 MHz	$P_{IN} = 55 \text{ W}$	$V_{CC} = 40 V$	325	350		W
hc	f = 1090 MHz	Pout = 325 W	$V_{CC} = 40 V$	40	45		%
GP	f = 1090 MHz	Pout = 325 W	$V_{CC} = 40 V$	7.7	8.0		dB

Pulse Conditions: Pulse width = 200μ s, Duty Cycle = 5%, are equivalent to the following

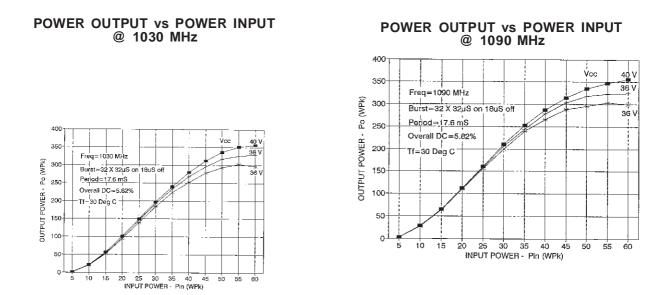
pulse burst conditions: Mode-S Interrogator (freq = 1030MHz)

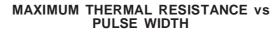
32 pulses, 32 μ s on, 18 μ s off, burst period = 17.6ms

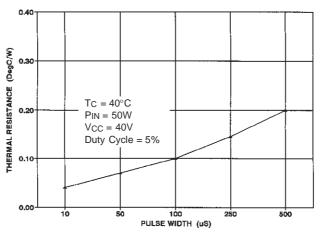
long term duty = 5.82%



TYPICAL PERFORMANCE

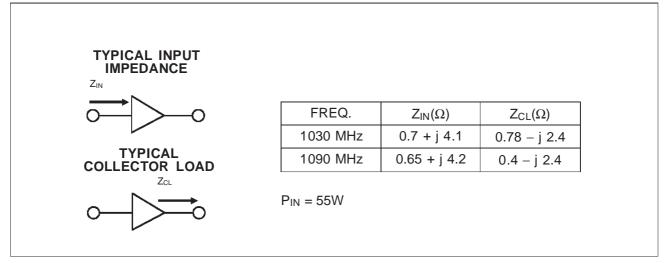




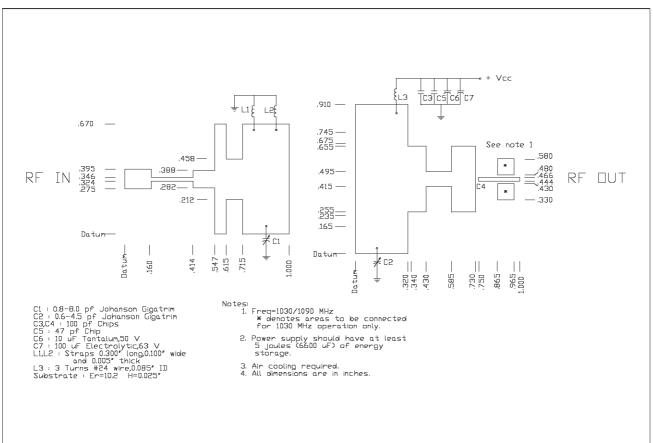




IMPEDANCE DATA

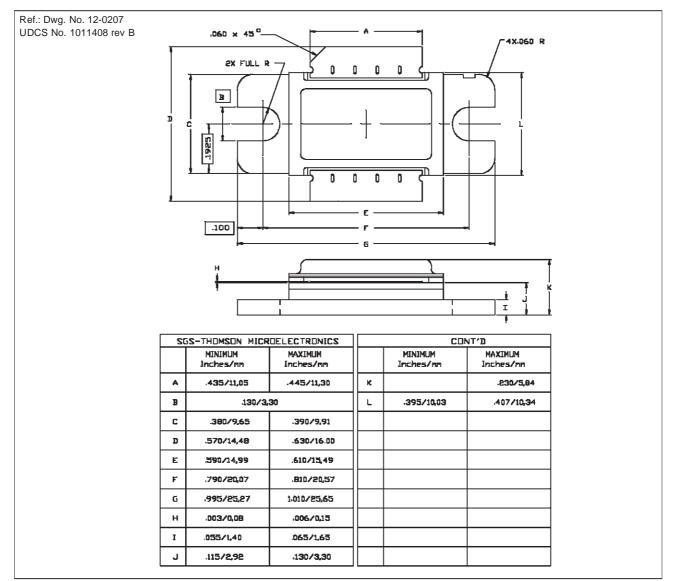


TEST CIRCUIT



SGS-THOMSON

PACKAGE MECHANICAL DATA



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